

Topographic Raman Imaging – Chemical Analysis and Profilometry in One Pass

TrueSurface Microscopy



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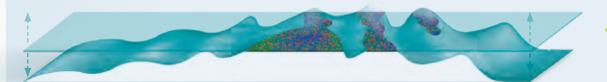
WITec's patented TrueSurface Microscopy option enables confocal Raman imaging guided by surface topography. Topographic Raman Imaging, a technique pioneered by WITec, uses an advanced optical profilometer integrated within the instrument to provide one-pass simultaneous operation.

3D chemical characterization on rough, inclined or irregularly-shaped samples can be carried out precisely along or at a set distance from a surface without requiring sample preparation.

Confocal Raman microscopes strongly reject out of focus light. The TrueSurface module allows the surface of even large or coarsely-textured samples to remain in constant focus during the measurement. As the sensor actively monitors and maintains a set distance between the objective and sample surface with sub-micrometer resolution, its closed-loop operation can eliminate any variations during measurements with long integration times.

Investigations of pharmaceutical coatings, geological samples, composite emulsions, complex semiconductor structures and many other applications can benefit from the accelerated workflow and methodological advantages provided by the new TrueSurface.

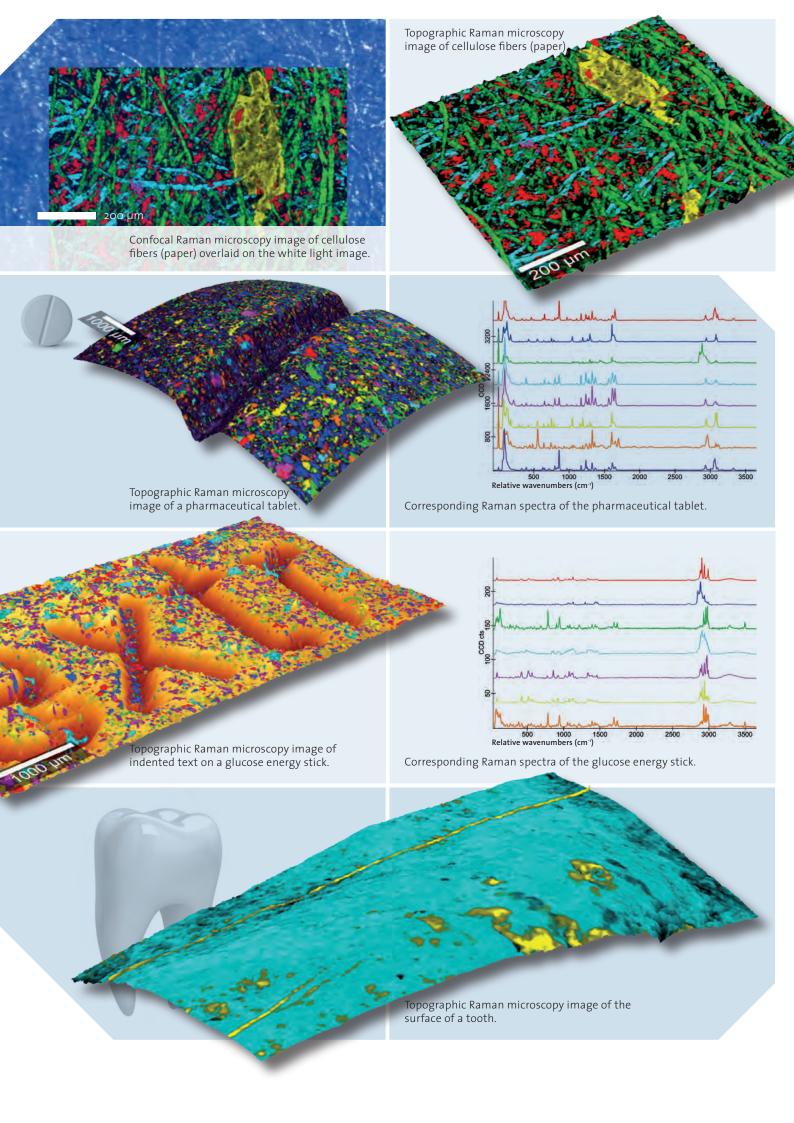




Confocal Raman imaging on large samples delivers an optical cross section of the sample. If the sample is not transparent, only the intersection of the focal plane and sample surface will give a Raman signal. Depending on the objective used, the focal plane might have a thickness of less than 1 μ m.



The TrueSurface Microscopy option enables the precise tracing of the surface while acquiring Raman imaging data, resulting in a topographic Raman image.



TrueSurface Microscopy -**Next Generation Topographic Raman Imaging**

The power of 3D confocal Raman imaging made more immediate and versatile than ever before. See your sample in relief and in depth.

- One-pass simultaneous optical profilometry and Raman imaging
- 3D chemical characterization on coarsely-textured or inclined samples
- No specialized sample preparation necessary
- Closed-loop operation eliminates variations during long measurements

TrueSurface Microscopy – Award-Winning Technology









Photonics Prism Award, PITTCON Editors' Gold Award, R&D 100 Award, Microscopy Today Innovation Award

WITec Headquarters

WITec GmbH Lise-Meitner-Straße 6 D-89081 Ulm . Germany Phone +49 (o) 731 140700 Fax +49 (o) 731 14070200 info@WITec.de www.WITec.de

WITec North America

WITec Instruments Corp. 130G Market Place Blvd Knoxville . TN 37922 . USA Phone 865 984 4445 Fax 865 984 4441 info@WITec-Instruments.com www.WITec-Instruments.com

WITec South East Asia

WITec Pte. Ltd. 25 International Business Park #03-59A German Centre Singapore 609916 Phone +65 9026 5667 shawn.lee@witec.biz

WITec China

WITec Beijing Representative Office Unit 507, Landmark Tower 1 8 North Dongsanhuan Road Beijing, PRC., 100004 Phone +86 (o) 10 6590 0577 Info.China@witec-instruments.com

WITec Japan

WITec K.K. KSP W713B Sakado 3-2-1 Takatsu-ku Kawasaki-shi Kanagawa 213-0012 Phone +81 44 19 7773 keiichi.nakamoto@witec-instruments.biz